Inventor: Wayne Renker
Title: "Process Condit Sensing Wafer and Data Analysis
System"
Sheet 1 of 10
Atty. Dkt. No.: M-12467 US

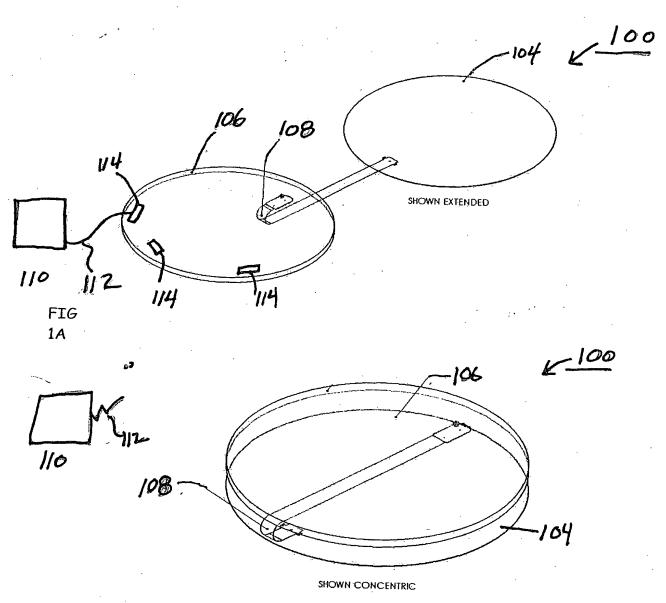
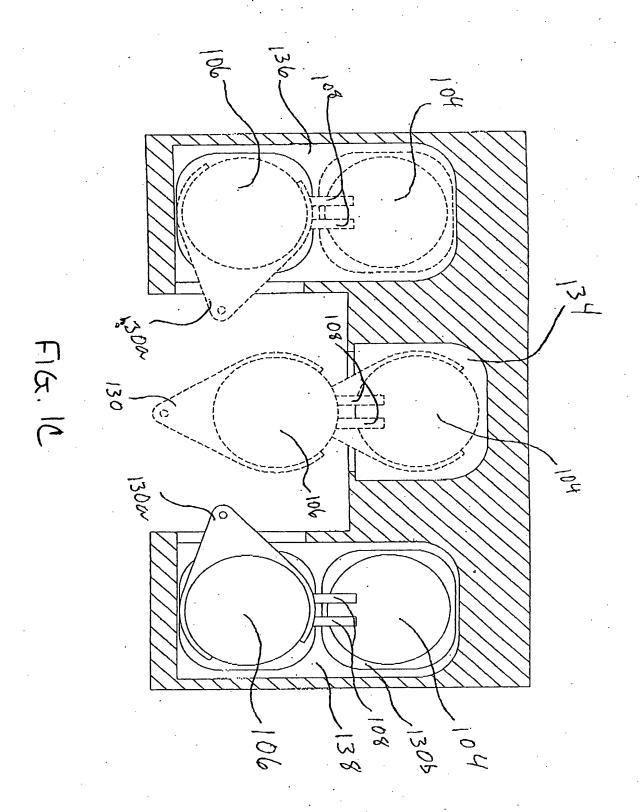
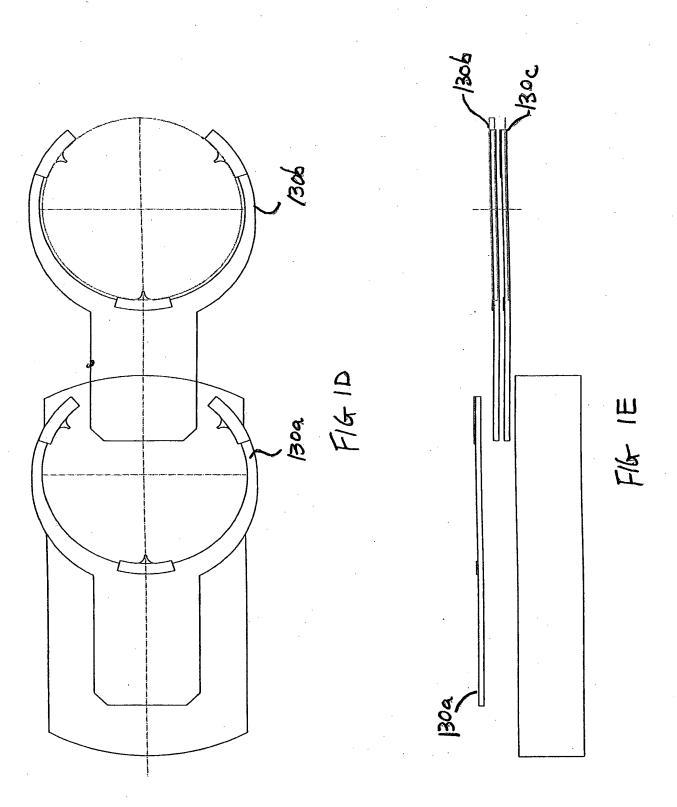


FIG 1B

Inventor: Wayne Renken
Title: "Process Condit Sensing Wafer and Data Analysis
System"
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Inventor: Wayne Renke Title: "Process Condition bensing Wafer and Data Analysis System" Sheet 3 of 10 Atty. Dkt. No.: M-12467 US



Inventor: Wayne Renken
Title: "Process Condi()Sensing Wafer and Data Analysis
System"
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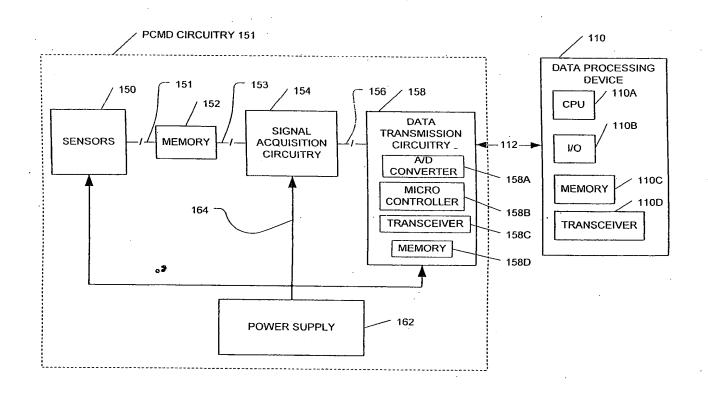
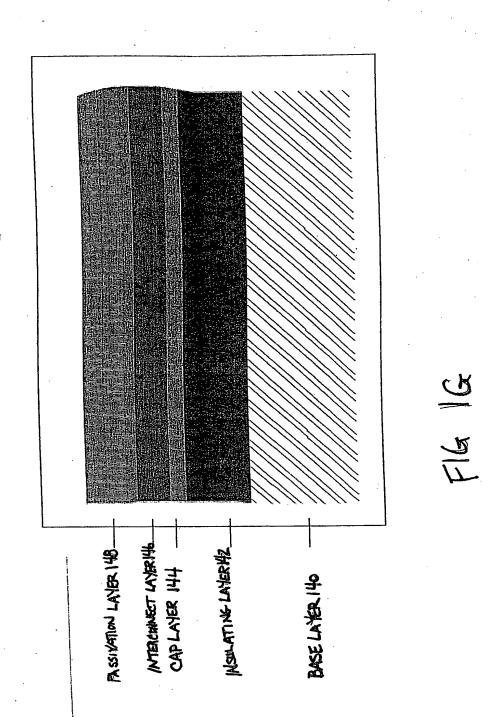
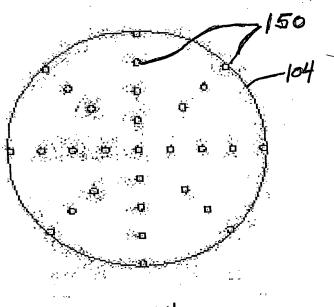


FIG 1F

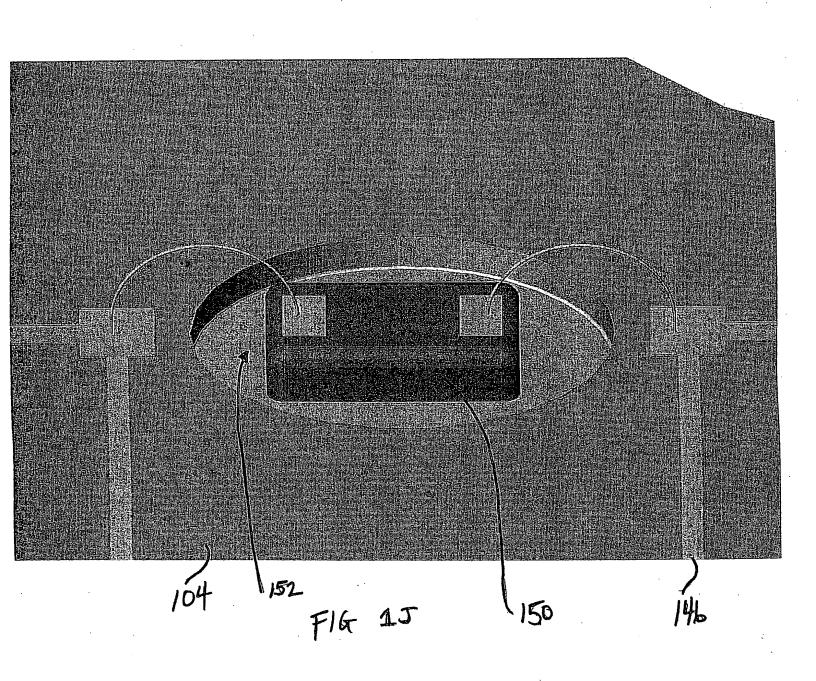
Inventor: Wayne Renker
Title: "Process Condition bensing Wafer and Data Analysis
- System"
Sheet 5 of 10 Atty. Dkt. No.: M-12467 US



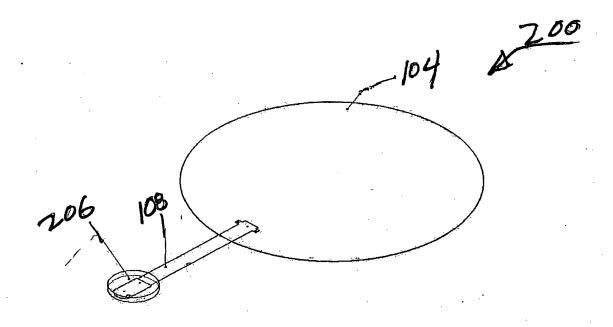
Inventor: Wayne Renkep
Title: "Process Conditio ensing Wafer and Data Analysis
'System"
Sheet 6 of 10
Atty. Dkt. No.: M-12467 US



Inventor: Wayne Renker
Title: "Process Condition Pensing Wafer and Data Analysis
System"
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Atty. Dkt. No.: M-12467 US



Inventor: Wayne Renken
Title: "Process Condition Insing Wafer and Data Analysis System"
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Atty. Dkt. No.: M-12467 US



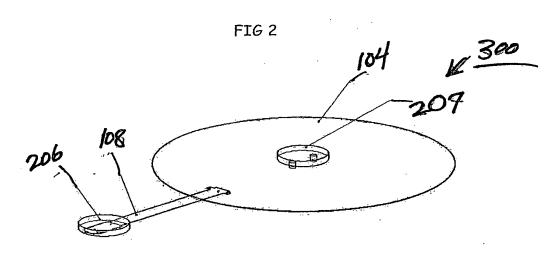
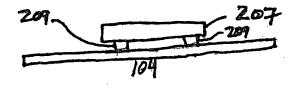


FIG 3A



F16:3B

Inventor: Wayne Renken
Title: "Process Conditio nsing Wafer and Data Analysis
System"
Sheet 9 of 10 Atty. Dkt. No.: M-12467 US

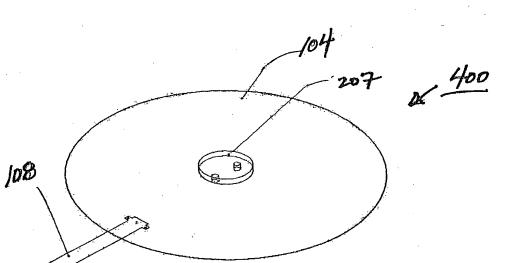


FIG 4

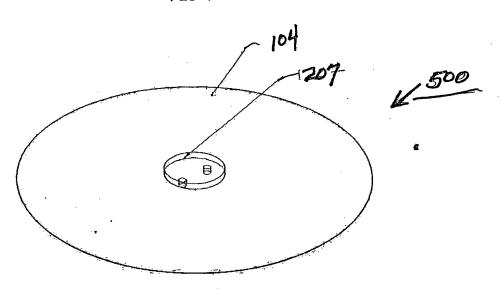


FIG 5

Inventor: Wayne Renken,
Title: "Process Condition Fensing Wafer and Data Analysis
System"
Sheet 10 of 10
Atty. Dkt. No.: M-12467 U

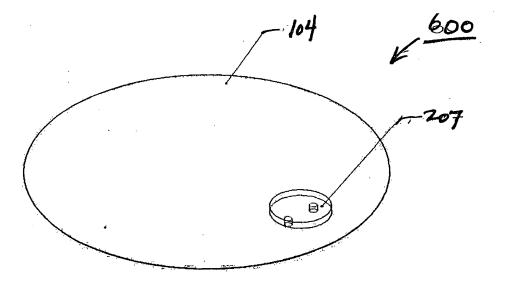


FIG6

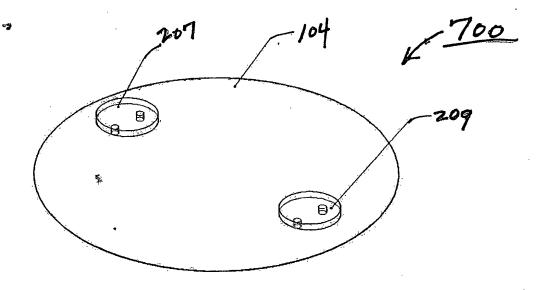


FIG 7